

**Notice of References Cited**

Application/Control No.

10/567,369

Applicant(s)/Patent Under  
Reexamination  
ICHINOSE ET AL.

Examiner

SARAH K. SALERNO

Art Unit

2814

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
	D	US-			
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	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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